

Nb₃Sn MATERIALS STUDIES

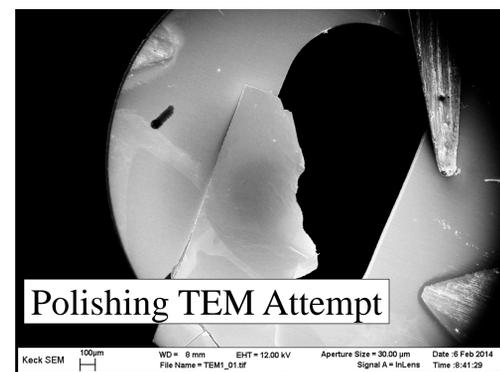
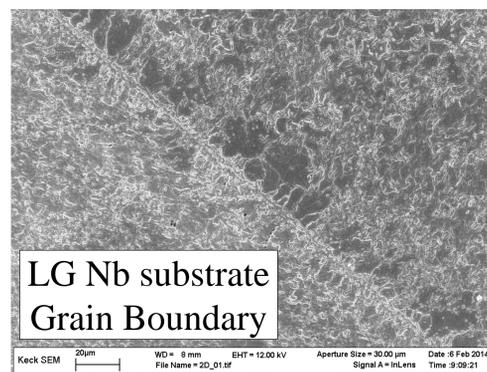
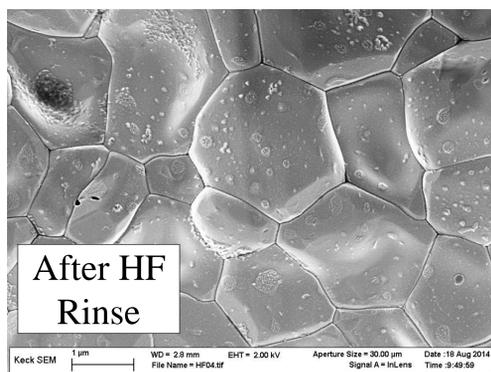
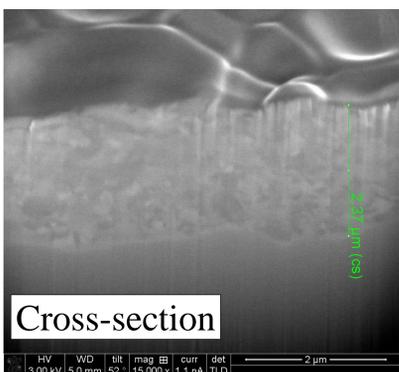
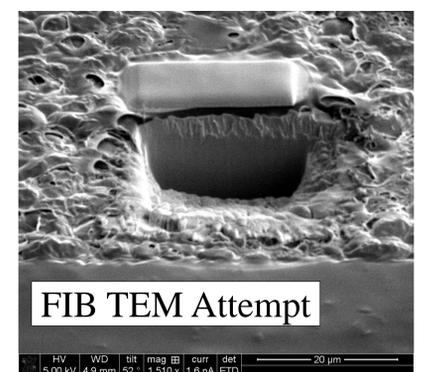
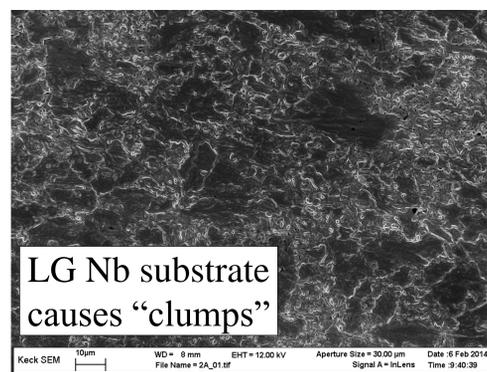
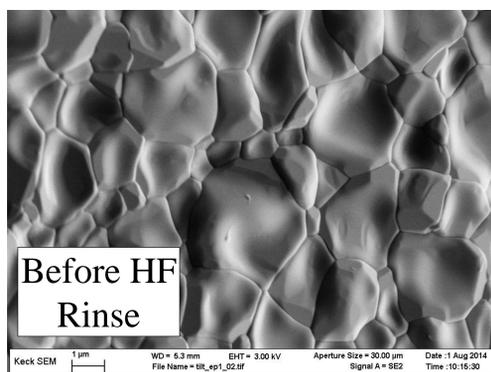
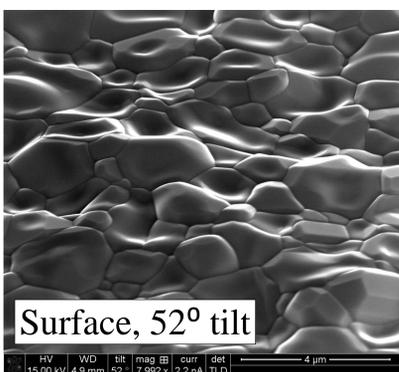
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Introduction

Nb₃Sn is a material with great potential for SRF applications, offering large potential gains in Q_0 and E_{acc} compared to niobium due to its large T_c and predicted B_{sh} . At Cornell, infrastructure has been developed to coat single cell 1.3 GHz niobium SRF cavities with Nb₃Sn using the vapor deposition technique. The first cavities produced have had very promising RF performances, achieving quality factors above 10^{10} at 4.2 K and 13 MV/m (see TUIOC03). In order to push performance further, it is important to better understand this material. In this work, we present both microscopic and bulk studies.

Microscopic Investigations

Superconducting behavior is determined by properties on the length scale of ξ (~3-4 nm) and λ (~100 nm), so it is important to understand the material on this scale in order to make correlations to its SRF properties. In this section we present microscopy studies performed with SEM/EDX and FIB.



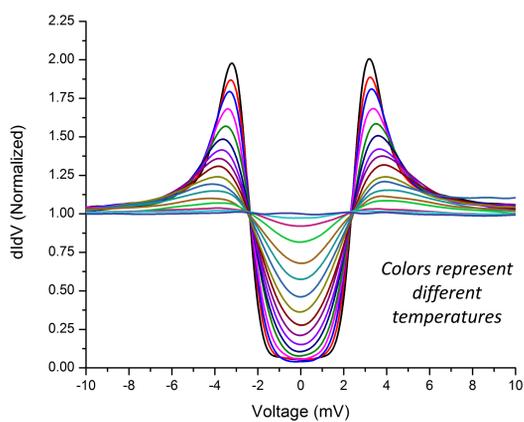
Typical coating is 2-3 μm thick with 1-2 μm grains

HF rinsing causes structures to appear on surface – EDX inconclusive

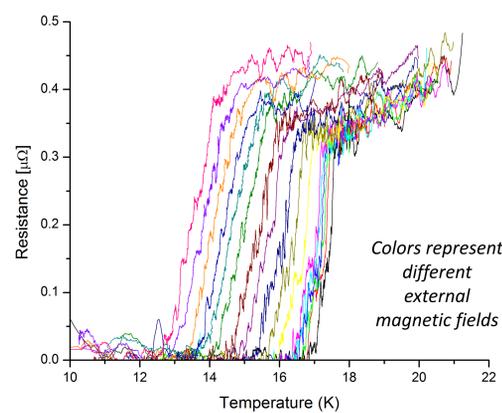
On large grain Nb substrate, Nb₃Sn grains smear together in some regions

Attempts to create TEM samples via FIB and polishing but no success yet

Bulk Investigations



Point contact tunneling at ANL measures superconducting energy gap as a function of temperature. The sharp gap indicates high superconducting quality at surface. Extracted values (red) for gap and critical temperature appear to follow correlations from [A. Godeke, Supercond. Sci. Tech. 19, R68 (2006)].



Upper critical magnetic field H_{c2} measured at ANL as a function of temperature by resistive method. Extracted $H_{c2}(T = 0 \text{ K})$ (red) appears to follow correlations by Godeke based on composition from EDX. H_{c2} calculated from material parameters measured in RF tests also shown (blue).

